

## 8-BIT SINGLE-CHIP MICROCONTROLLER

## DESCRIPTION

The  $\mu$ PD780001 is a product of the 78K/0 Series of microcontrollers, and features internal 8-bit resolution A/D converters, timers, serial interface units, interrupt controllers, and many other incorporated peripheral hardware.

A one-time PROM or EPROM version ( $\mu$ PD78P018F) and various development tools for the  $\mu$ PD780001 are available. The  $\mu$ PD78P018F is capable of operating in the same power supply voltage range as the  $\mu$ PD780001.

Functions are described in detail in the following User's Manuals. They should be read before starting design.

$\mu$ PD780001 User's Manual : In preparation  
78K/0 Series User's Manual—Instruction : IEU-1372

## FEATURES

- Internal ROM and RAM
  - Internal ROM : 8 Kbytes
  - Internal high-speed RAM : 192 bytes
- Two types of packages are provided:
  - 64-pin plastic shrink DIP (750 mil)
  - 64-pin plastic QFP (14 × 14 mm)
- Instruction execution time can be varied from high-speed (0.4  $\mu$ s) to low-speed (6.4  $\mu$ s)
- I/O ports : 39
- 8-bit resolution A/D converter : 8 channels
- Serial interface : 1 channel
  - 3-wire serial I/O mode : 1 channel
- Timer : 3 channels
- Supply voltage :  $V_{DD} = 2.7$  to 5.5 V

## APPLICATIONS

Telephones, VCRs, audio equipment, cameras, air conditioners, home appliances, pagers, etc.

## ORDERING INFORMATION

Part Number	Package
$\mu$ PD780001CW-xxx	64-pin plastic shrink DIP (750 mil)
$\mu$ PD780001GC-xxx-AB8	64-pin plastic QFP (14 × 14 mm)

**Remark** xxx indicates ROM code suffix.

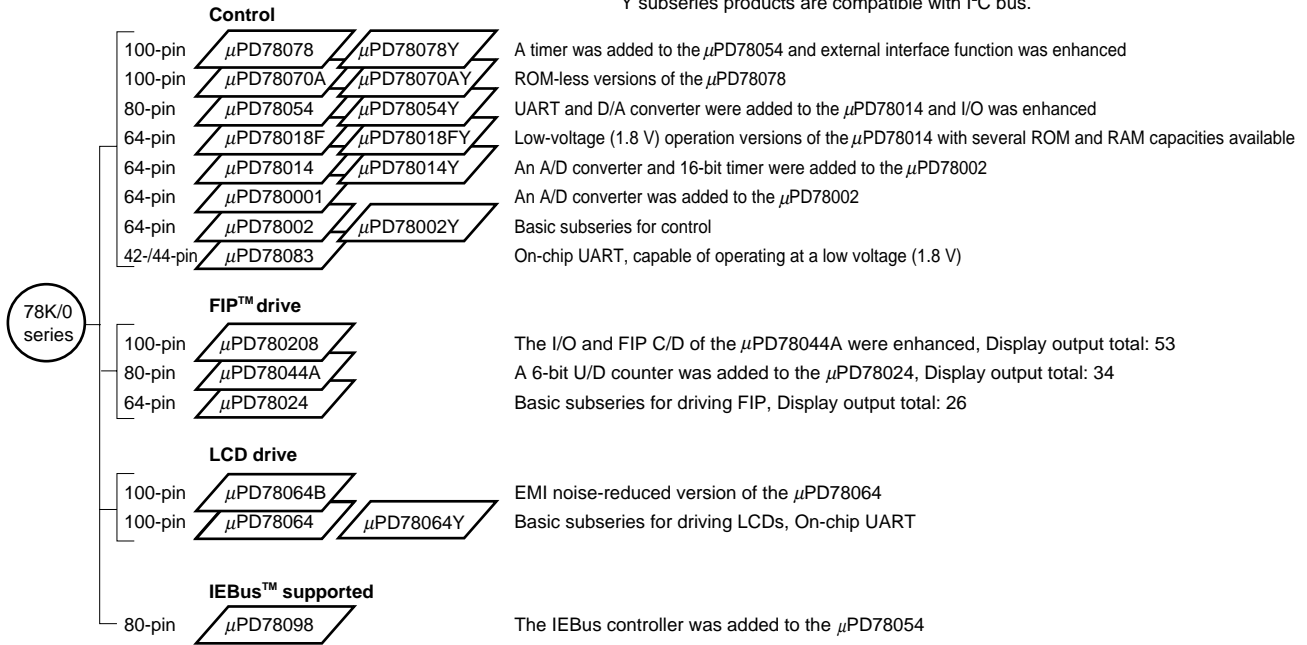
The information in this document is subject to change without notice.

\* 78K/0 Series Development

The following shows the 78K/0 series products development. Subseries names are shown inside frames.



Y subseries products are compatible with I<sup>2</sup>C bus.



The following table shows the differences among subseries functions.

Function Part Number		ROM Capacity	Timer				8-bit A/D	8-bit D/A	Serial Interface	I/O	V <sub>DD</sub> MIN. Value	External Expansion
			8-bit	16-bit	Watch	WDT						
Control	μPD78078	32 K-60 K	4ch	1ch	1ch	1ch	8ch	2ch	3ch (UART: 1ch)	88	1.8 V	Available
	μPD78070A	–								61	2.7 V	
	μPD78054	16 K-60 K	2ch	–	–	–	–	2ch	69	2.0 V		
	μPD78018F	8 K-60 K							53	1.8 V		
	μPD78014	8 K-32 K							2.7 V			
	μPD780001	8 K	–	–	–	–	–	1ch	39	2.7 V	Not available	
	μPD78002	8 K-16 K							53		Available	
	μPD78083	–							8ch	1ch (UART: 1ch)	33	1.8 V
FIP drive	μPD780208	32 K-60 K	2ch	1ch	1ch	1ch	8ch	–	2ch	74	2.7 V	Not available
	μPD78044A	16 K-40 K								68		
	μPD78024	24 K-32 K								54		
LCD drive	μPD78064B	32 K	2ch	1ch	1ch	1ch	8ch	–	2ch (UART: 1ch)	57	2.0 V	Not available
	μPD78064	16 K-32 K										
IEBus supported	μPD78098	32 K-60 K	2ch	1ch	1ch	1ch	8ch	2ch	3ch (UART: 1ch)	69	2.7 V	Available

**FUNCTION DESCRIPTION**

Item		Function
Internal memory	ROM	8 Kbytes
	Internal high-speed RAM	192 bytes
Memory space		64 Kbytes
General register		8 bits × 32 registers (8 bits × 8 registers × 4 banks)
Instruction cycles		Instruction execution time variable function is integrated. 0.4 μs/0.8 μs/1.6 μs/3.2 μs/6.4 μs (@ 10.0 MHz operation with main system clock)
Instruction set		<ul style="list-style-type: none"> <li>• 16-bit operation</li> <li>• Multiply/divide (8 bits × 8 bits, 16 bits ÷ 8 bits)</li> <li>• Bit manipulate (set, reset, test, Boolean operation)</li> <li>• BCD adjust, etc.</li> </ul>
I/O ports		Total : 39 <ul style="list-style-type: none"> <li>• CMOS input : 4</li> <li>• CMOS input/output : 35</li> </ul>
A/D converter		<ul style="list-style-type: none"> <li>• 8-bit resolution × 8 channels</li> <li>• Operable over a wide power supply voltage range: V<sub>DD</sub> = 2.7 to 5.5 V</li> </ul>
Serial interface		3-wire serial I/O mode: 1 channel
Timer		<ul style="list-style-type: none"> <li>• 8-bit timer/event counter: 2 channels</li> <li>• Watchdog timer: 1 channel</li> </ul>
Timer output		2
Clock output		39.1 kHz, 78.1 kHz, 156 kHz, 313 kHz, 625 kHz, 1.25 MHz (@ 10.0 MHz operation with main system clock)
Buzzer output		2.4 kHz, 4.9 kHz, 9.8 kHz (@ 10.0 MHz operation with main system clock)
Vectored interrupts	Maskable interrupts	Internal: 5, External: 3
	Non-Maskable interrupt	Internal: 1
	Software interrupt	Internal: 1
Test input		External: 1
Supply voltage		V <sub>DD</sub> = 2.7 to 5.5 V
Operating ambient temperature		T <sub>A</sub> = -40 to +85°C
Package		<ul style="list-style-type: none"> <li>• 64-pin plastic shrink DIP (750 mil)</li> <li>• 64-pin plastic QFP (14 × 14 mm)</li> </ul>

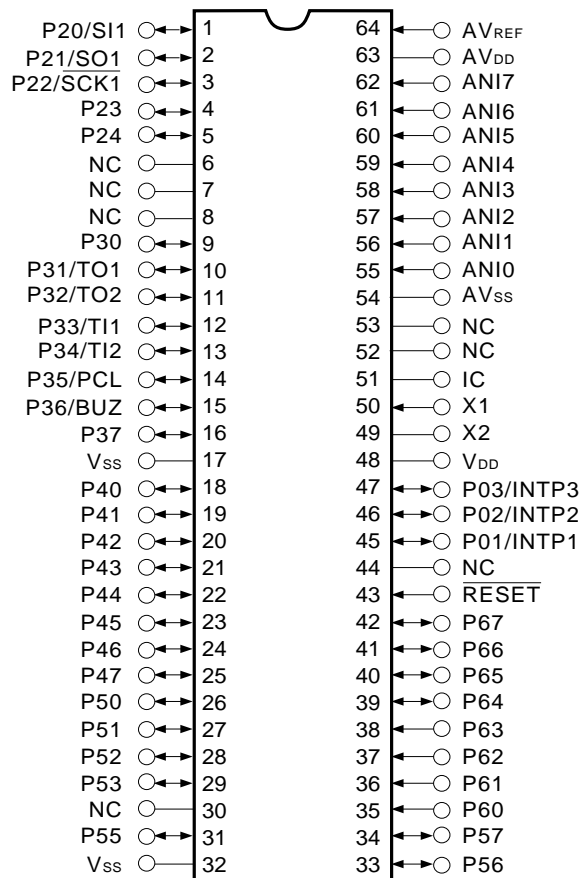
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1. PIN CONFIGURATION (Top View)

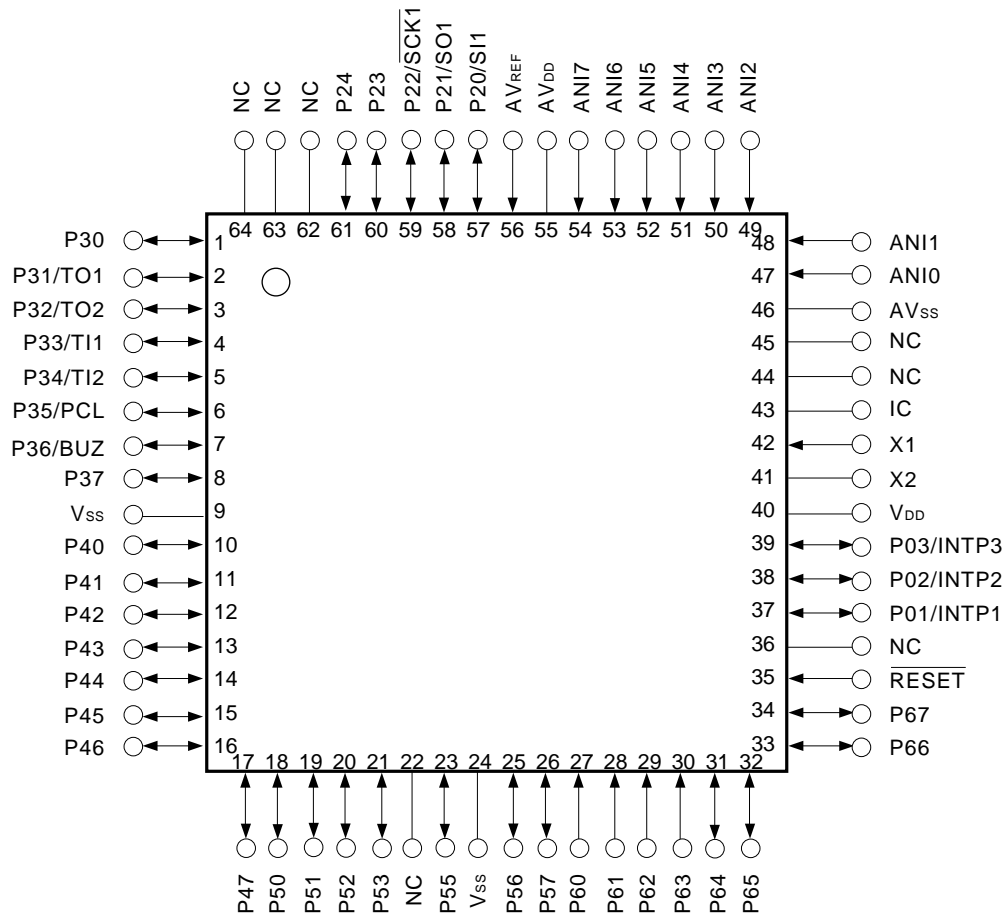
- 64-Pin Plastic Shrink DIP (750 mil)

μPD780001CW-xxx



- Cautions**
1. Always connect the IC (Internally Connected) pin to Vss directly.
  2. Always connect the NC (Non-connection) pin to Vss (However, can also be left open).
  3. Always connect the AVDD pin to VDD.
  4. Always connect the AVss pin to Vss.

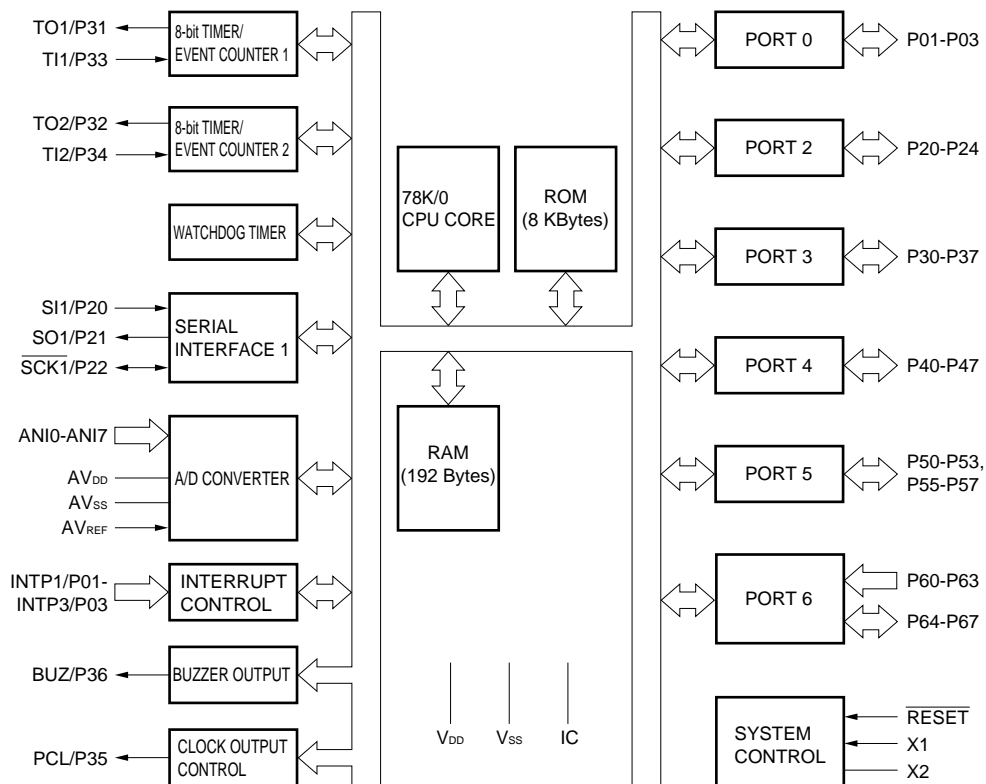
- 64-Pin Plastic QFP (14 x 14 mm)  
μPD780001GC-xxx-AB8



- Cautions**
1. Always connect the IC (Internally Connected) pin to Vss directly.
  2. Always connect the NC (Non-connection) pin to Vss (However, can also be left open).
  3. Always connect the AVDD pin to VDD.
  4. Always connect the AVss pin to Vss.

P01-P03	: Port 0	PCL	: Programmable Clock
P20-P24	: Port 2	BUZ	: Buzzer Clock
P30-P37	: Port 3	X1, X2	: Crystal
P40-P47	: Port 4	RESET	: Reset
P50-P53, P55-P57	: Port 5	ANI0-ANI7	: Analog Input
P60-P67	: Port 6	AVDD	: Analog Power Supply
INTP1-INTP3	: Interrupt from Peripherals	AVSS	: Analog Ground
TI1, TI2	: Timer Input	AVREF	: Analog Reference Voltage
TO1, TO2	: Timer Output	VDD	: Power Supply
SI1	: Serial Input	VSS	: Ground
SO1	: Serial Output	IC	: Internally Connected
SCK1	: Serial Clock	NC	: Non-Connection

2. BLOCK DIAGRAM





### 3. PIN FUNCTIONS

#### 3.1 Port Pins

Pin Name	I/O	Function	After Reset	Alternate Function
P01-P03	Input/ output	Port 0 3-bit input/output port. Input/output can be specified bit-wise. When used as an input port, pull-up resistor can be connected by software.	Input	INTP1- INTP3
P20	Input/ output	Port 2 5-bit input/output port. Input/output can be specified bit-wise. When used as an input port, pull-up resistor can be connected by software.	Input	SI1
P21				SO1
P22				SCK1
P23, 24				—
P30	Input/ output	Port 3 8-bit input/output port. Input/output can be specified bit-wise. When used as an input port, pull-up resistor can be connected by software.	Input	—
P31				TO1
P32				TO2
P33				TI1
P34				TI2
P35				PCL
P36				BUZ
P37				—
P40-P47	Input/ output	Port 4 8-bit input/output port. Input/output can be specified in 8-bit units. When used as an input port, pull-up resistor can be connected by software. Test input flag (KRIF) is set to 1 by falling edge detection.	Input	—
P50-P53, P55-P57	Input/ output	Port 5 7-bit input/output port. LEDs can be driven directly. Input/output can be specified bit-wise. When used as an input port, pull-up resistor can be connected by software.	Input	—
P60-P63	Input	Port 6 8-bit input/output port.	Input only.	—
P64-P67	Input/ output		Input/output can be specified bit-wise. When used as an input port, pull-up resistor can be connected by software.	Input

3.2 Non-port Pins

Pin Name	I/O	Function	After Reset	Alternate Function
INTP1	Input	External interrupt input by which the effective edge (rising edge, falling edge, or both rising edge and falling edge) can be specified.	Input	P01
INTP2				P02
INTP3		Falling edge detection external interrupt input.		P03
SI1	Input	Serial interface serial data input.	Input	P20
SO1	Output	Serial interface serial data output.	Input	P21
SCK1	Input/ output	Serial interface serial clock input/output.	Input	P22
TI1	Input	External count clock input to 8-bit timer (TM1).	Input	P33
TI2		External count clock input to 8-bit timer (TM2).		P34
TO1	Output	8-bit timer output.	Input	P31
TO2				P32
PCL	Output	Clock output (for main system clock trimming).	Input	P35
BUZ	Output	Buzzer output.	Input	P36
ANI0-ANI7	Input	A/D converter analog input.	Input	—
AVREF	Input	A/D converter reference voltage input.	—	—
AVDD	—	A/D converter analog power supply. Connected to VDD.	—	—
AVSS	—	A/D converter ground potential. Connected to VSS.	—	—
RESET	Input	System reset input.	—	—
X1	Input	Main system clock oscillation crystal connection.	—	—
X2	—		—	—
VDD	—	Positive power supply.	—	—
VSS	—	Ground potential.	—	—
IC	—	Internally connected. Connected to VSS directly.	—	—
NC	—	Not internally connected. Connected to VSS (Also can be left open).	—	—

**3.3 Pin I/O Circuits and Recommended Connection of Unused Pins**

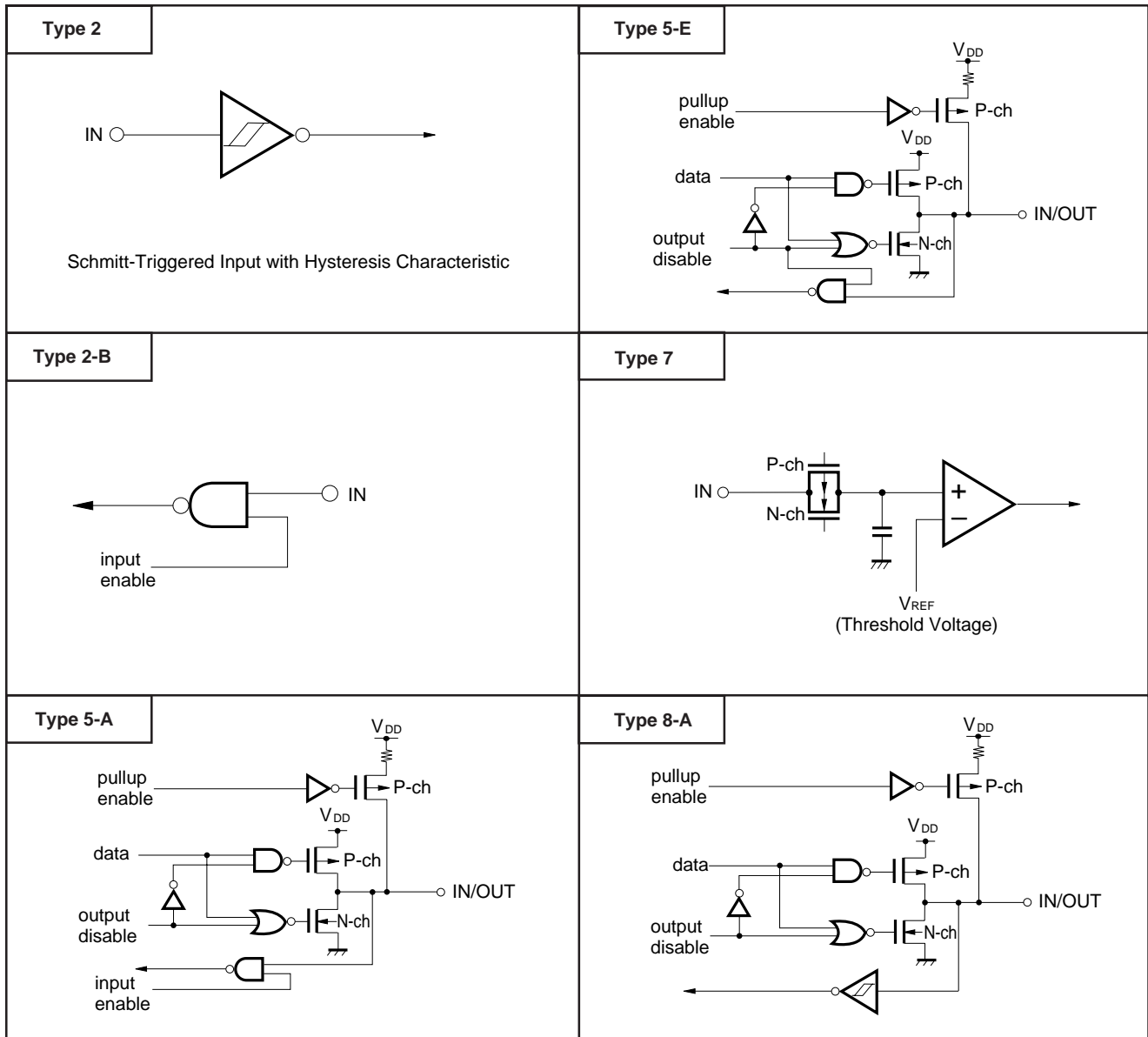
The input/output circuit type of each pin and recommended connection of unused pins are shown in Table 3-1. For the input/output circuit configuration of each type, see Figure 3-1.

**Table 3-1. Types of Pin Input/Output Circuit**

Pin Name	Input/Output Circuit Type	Input/Output	Recommended Connection when Not Used		
P01/INTP1	8-A	Input/output	Independently connected to V <sub>SS</sub> through resistor.		
P02/INTP2					
P03/INTP3					
ANI0-ANI7	7	Input	Connected to V <sub>DD</sub> or V <sub>SS</sub> .		
P20/SI1	8-A	Input/output	Independently connected to V <sub>DD</sub> or V <sub>SS</sub> through resistor.		
P21/SO1	5-A				
P22/SCK1	8-A				
P23	5-A				
P24	8-A				
P30	5-A				
P31/TO1					
P32/TO2					
P33/TI1	8-A				
P34/TI2	5-A				
P35/PCL					
P36/BUZ					
P37					
P40-P47	5-E			Input/output	Independently connected to V <sub>DD</sub> through resistor.
P50-P53	5-A			Input/output	Independently connected to V <sub>DD</sub> or V <sub>SS</sub> through resistor.
P55-P57					
P60-P63	2-B	Input	Connected to V <sub>DD</sub> or V <sub>SS</sub> .		
P64-P67	5-A	Input/output	Independently connected to V <sub>DD</sub> or V <sub>SS</sub> through resistor.		
RESET	2	Input	—		
AVREF	—	—	Connected to V <sub>SS</sub> .		
AVDD			Connected to V <sub>DD</sub> .		
AVSS			Connected to V <sub>SS</sub> .		
IC			Connected to V <sub>SS</sub> directly.		
NC			Connected to V <sub>SS</sub> (Also can be left open).		

**Caution** The connection of the NC pin differs from that of the PROM version (μPD78P018F).

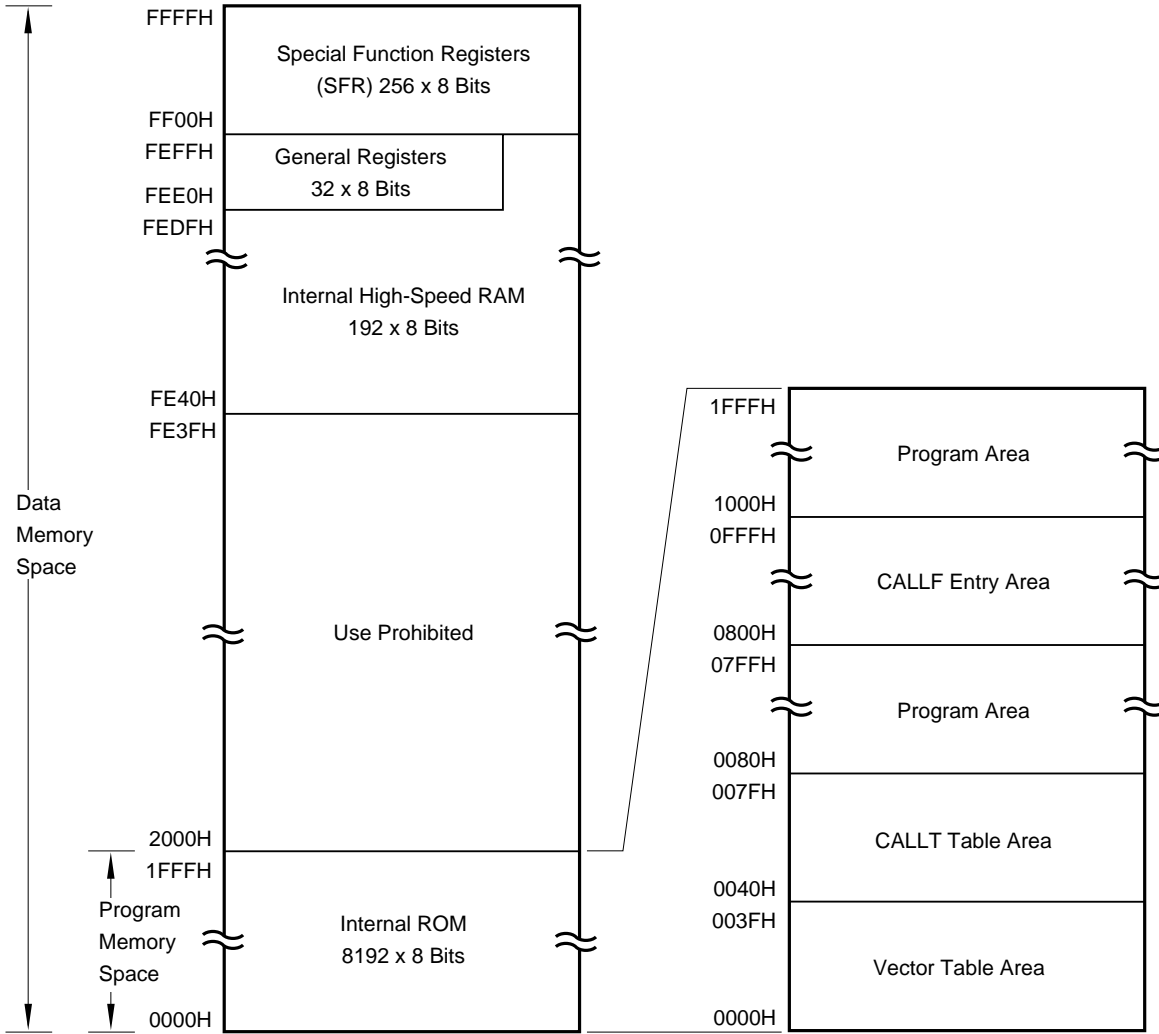
Figure 3-1. Pin Input/Output Circuits



4. MEMORY SPACE

The memory map of the μPD780001 is shown in Figure 4-1.

Figure 4-1. Memory Map



## 5. PERIPHERAL HARDWARE FUNCTION FEATURES

### 5.1 Ports

The following two types of I/O ports are provided.

- CMOS input (P60-P63) : 4
- CMOS input/output (port 0, port 2-port 5, P64-P67) : 35

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Total : 39

**Table 5-1. Functions of Ports**

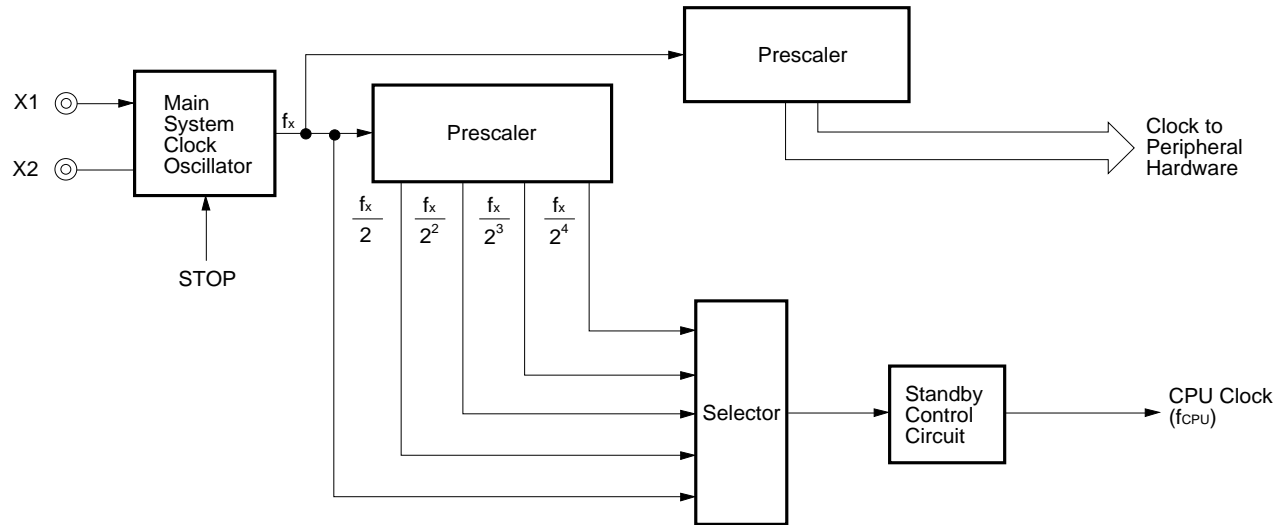
Port Name	Pin Name	Function
Port 0	P01-P03	Input/output ports. Input/output can be specified bit-wise. When used as an input port, on-chip pull-up resistor can be connected by software.
Port 2	P20-P24	Input/output ports. Input/output can be specified bit-wise. When used as an input port, on-chip pull-up resistor can be connected by software.
Port 3	P30-P37	Input/output ports. Input/output can be specified bit-wise. When used as an input port, on-chip pull-up resistor can be connected by software.
Port 4	P40-P47	Input/output ports. Input/output can be specified in 8-bit units. When used as an input port, on-chip pull-up resistor can be connected by software. Test input flag (KRIF) is set to 1 by falling edge detection.
Port 5	P50-P53, P55-P57	Input/output ports. Input/output can be specified bit-wise. When used as an input port, on-chip pull-up resistor can be connected by software. LEDs can be driven directly.
Port 6	P60-P63	Input-only port.
	P64-P67	Input/output ports. Input/output can be specified bit-wise. When used as an input port, on-chip pull-up resistor can be connected by software.

### 5.2 Clock Generator

An on-chip main system clock generator is provided.  
 The instruction execution time can be changed.

- 0.4 μs/0.8 μs/1.6 μs/3.2 μs/6.4 μs (Main system clock: at 10.0-MHz operation)

**Figure 5-1. Clock Generator Block Diagram**



### 5.3 Timer/Event Counter

The following three channels are incorporated in the timer/event counter.

- 8-bit timer/event counter : 2 channels
- Watchdog timer : 1 channel

**Table 5-2. Types and Functions of Timer/Event Counter**

		8-bit Timer/Event Counter	Watchdog Timer
Type	Interval timer	2 channels	1 channel
	External event counter	2 channels	–
Functions	Timer output	2 outputs	–
	Square wave output	2 outputs	–
	Interrupt request	2	1



Figure 5-2. 8-bit Timer/Event Counter Block Diagram

\*

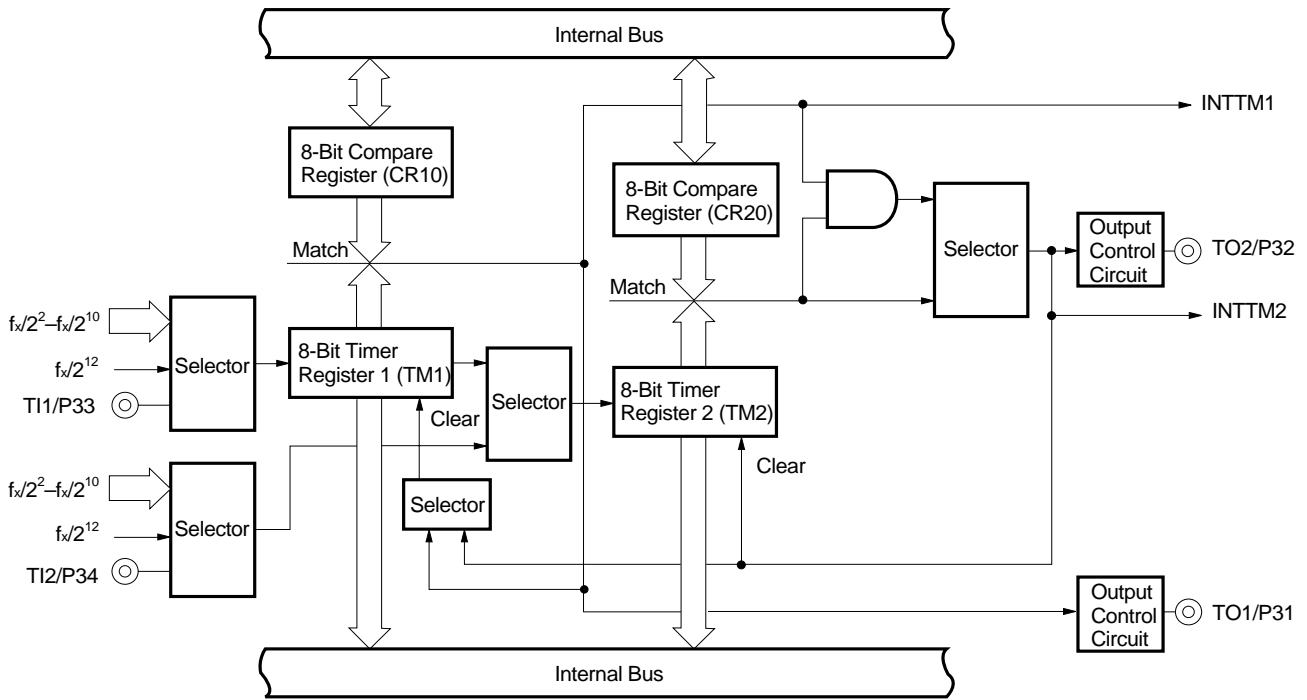
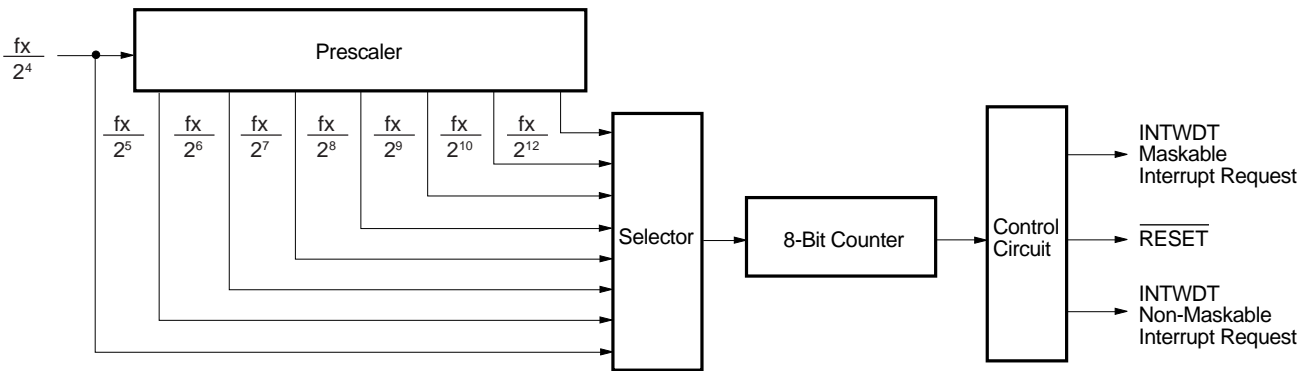


Figure 5-3. Watchdog Timer Block Diagram

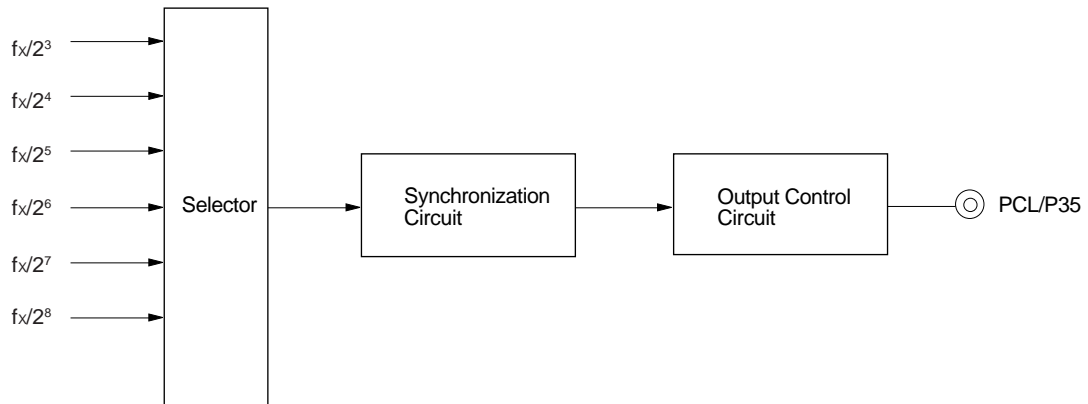


### 5.4 Clock Output Control Circuit

The clock with the following frequencies can be output for clock output.

- 39.1 kHz/78.1 kHz/156 kHz/313 kHz/625 kHz/1.25 MHz (Main system clock: at 10.0-MHz operation)

**Figure 5-4. Clock Output Control Circuit Block Diagram**

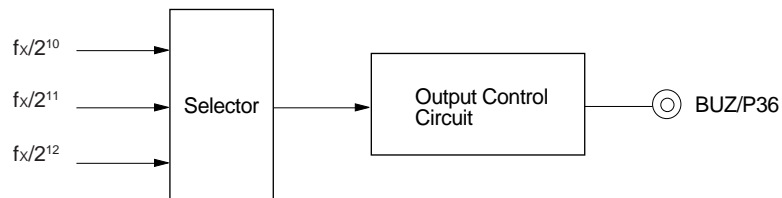


### 5.5 Buzzer Output Control Circuit

A clock with the following frequencies can be output for buzzer output.

- 2.4 kHz/4.9 kHz/9.8 kHz (Main system clock: at 10.0-MHz operation)

**Figure 5-5. Buzzer Output Control Circuit Block Diagram**

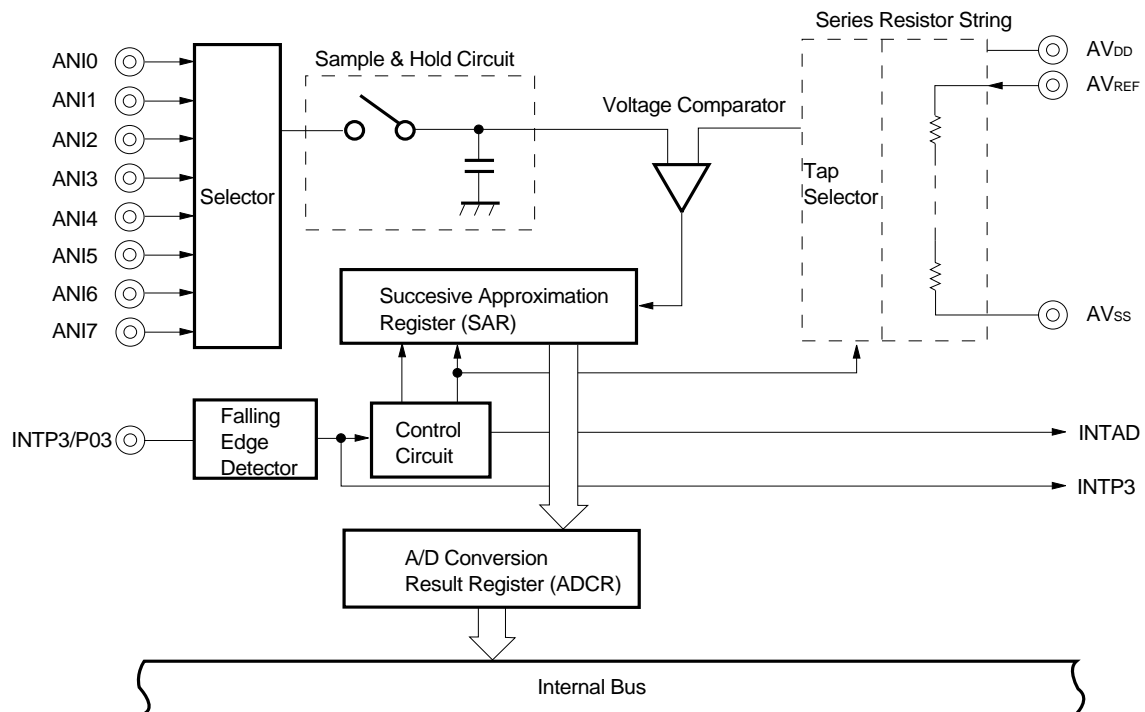


5.6 A/D Converter

The A/D converter has on-chip eight 8-bit resolution channels.  
 There are the following two methods to start A/D conversion.

- Hardware starting
- Software starting

Figure 5-6. A/D Converter Block Diagram

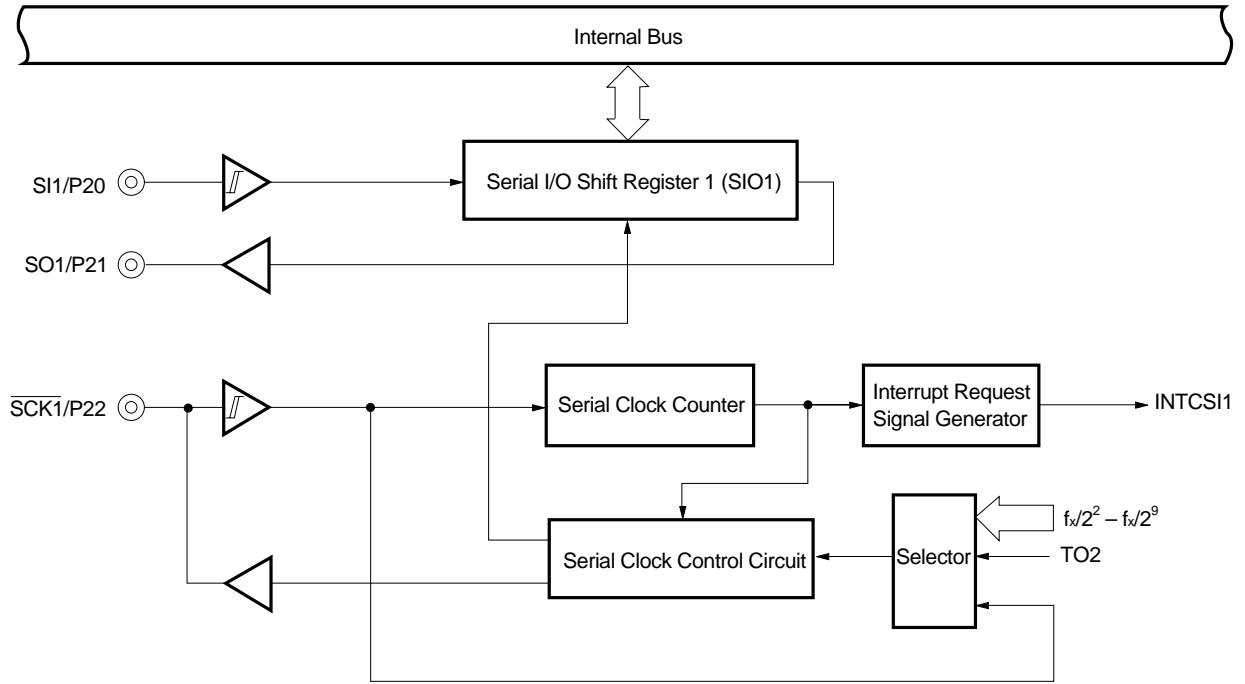


5.7 Serial Interface

One on-chip clocked serial interface is provided.

Serial interface channel 1 operates in MSB/LSB-first switchable 3-wire serial I/O mode.

Figure 5-7. Serial Interface Channel 1 Block Diagram



## 6. INTERRUPT FUNCTIONS AND TEST FUNCTION

### 6.1 Interrupt Functions

There are 10 interrupt functions of 3 different kinds as shown below.

- Non-maskable interrupt : 1
- Maskable interrupts : 8
- Software interrupt : 1

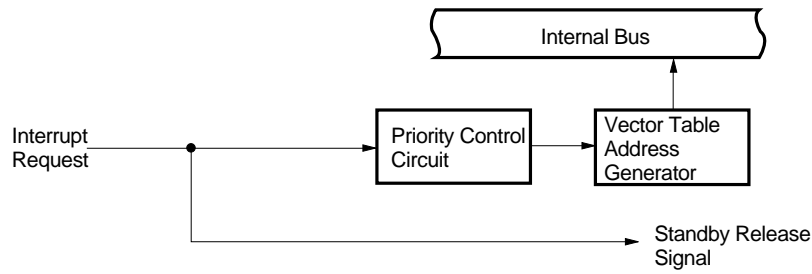
**Table 6-1. Interrupt Source List**

Interrupt Type	Default Priority <sup>Note 1</sup>	Interrupt Source		Internal/External	Vector Table Address	Basic <sup>Note 2</sup> Configuration Type
		Name	Trigger			
Non-maskable	—	INTWDT	Watchdog timer overflow (with watchdog timer mode 1 selected)	Internal	0004H	(A)
Maskable	0	INTWDT	Watchdog timer overflow (with interval timer mode selected)			
	1	INTP1	Pin input edge detection	External	0008H	(C)
	2	INTP2			000AH	
	3	INTP3			000CH	
	4	INTCS1	Serial interface channel 1 transfer end	Internal	0010H	(B)
	5	INTTM1	8-bit timer/event counter 1 match signal generation		0016H	
	6	INTTM2	8-bit timer/event counter 2 match signal generation		0018H	
	7	INTAD	A/D converter conversion end		001AH	
Software	—	BRK	BRK instruction execution	Internal	003EH	(D)

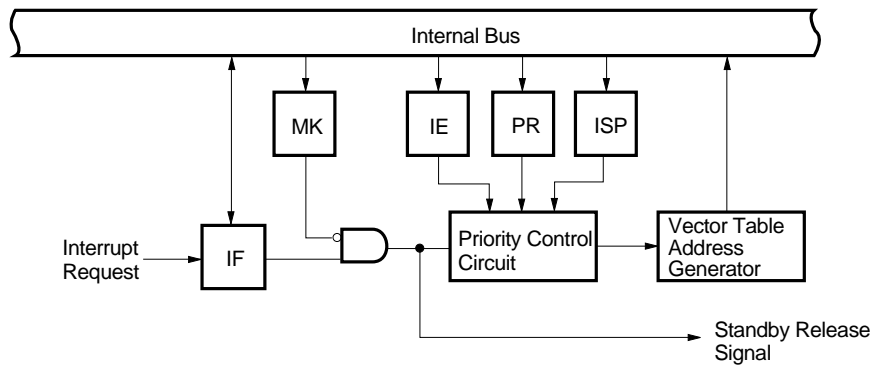
- Notes**
1. The default priority is the priority applicable when more than one maskable interrupt is generated. 0 is the highest priority and 7, the lowest.
  2. Basic configuration types (A) - (D) correspond to those on Figure 6-1.

Figure 6-1. Interrupt Function Basic Configuration (1/2)

(A) Internal Non-Maskable Interrupt



(B) Internal Maskable Interrupt (IMI)



(C) External Maskable Interrupt (EMI)

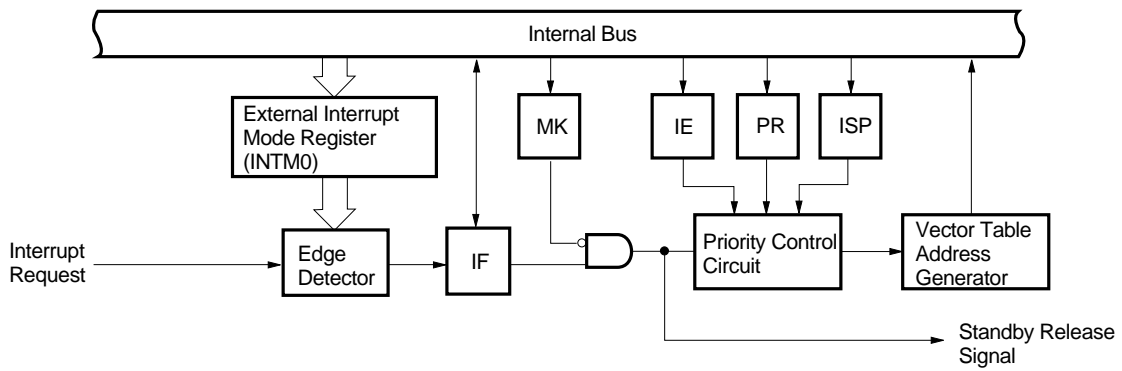
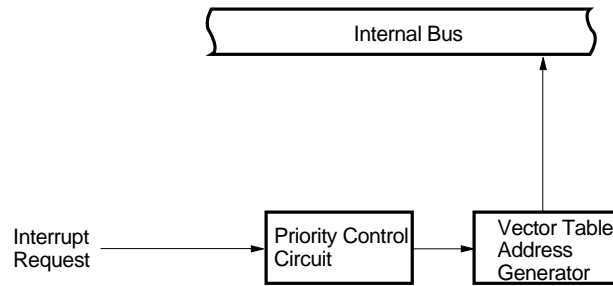


Figure 6-1. Interrupt Function Basic Configuration (2/2)

(D) Software Interrupt



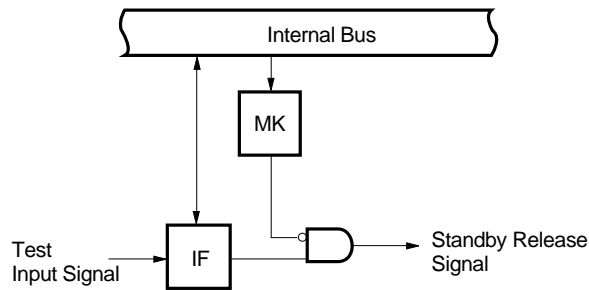
- IF : Interrupt request flag
- IE : Interrupt enable flag
- ISP : In-service priority flag
- MK : Interrupt mask flag
- PR : Priority specification flag

6.2 Test Function

The following one test function is provided.

Test Source		Internal/External
Name	Trigger	
INTPT4	Port 4 falling edge detection	External

Figure 6-2. Test Function Basic Configuration



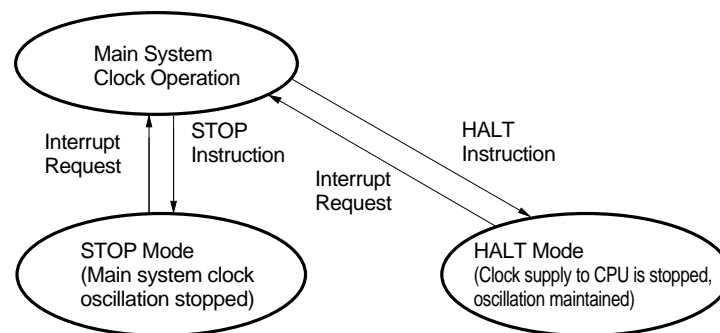
- IF : Test input flag
- MK : Test mask flag

## 7. STANDBY FUNCTIONS

There are the following two standby functions to reduce the current consumption.

- HALT mode : The CPU operating clock is stopped. The average current consumption can be reduced by intermittent operation in combination with the normal operating mode.
- STOP mode : The main system clock oscillation is stopped. The whole operation by the main system clock is stopped, so that the system operates with ultra-low power dissipation.

Figure 7-1. Standby Functions



## 8. RESET FUNCTIONS

There are the following two reset methods.

- External reset input by  $\overline{\text{RESET}}$  pin.
- Internal reset by watchdog timer runaway time detection.



9. INSTRUCTION SET

(1) 8-Bit Instruction

MOV, XCH, ADD, ADDC, SUB, SUBC, AND, OR, XOR, CMP, MULU, DIVUW, INC, DEC, ROR, ROL, RORC, ROLC, ROR4, ROL4, PUSH, POP, DBNZ

2nd Operand 1st Operand	#byte	A	r <sup>Note</sup>	sfr	saddr	laddr16	PSW	[DE]	[HL]	[HL+byte] [HL+B] [HL+C]	\$addr16	1	None
A	ADD ADDC SUB SUBC AND OR XOR CMP		MOV XCH ADD ADDC SUB SUBC AND OR XOR CMP	MOV XCH	MOV XCH	MOV XCH	MOV	MOV XCH	MOV XCH	MOV XCH		ROR ROL RORC ROLC	
r	MOV	MOV ADD ADDC SUB SUBC AND OR XOR CMP											INC DEC
r1											DBNZ		
sfr	MOV	MOV											
saddr	MOV ADD ADDC SUB SUBC AND OR XOR CMP	MOV									DBNZ		INC DEC
laddr16		MOV											
PSW	MOV	MOV											PUSH POP
[DE]		MOV											
[HL]		MOV											ROR4 ROL4
[HL+byte] [HL+B] [HL+C]		MOV											
X													MULU
C													DIVUW

Note Except r=A

**(2) 16-Bit Instruction**

MOVW, XCHW, ADDW, SUBW, CMPW, PUSH, POP, INCW, DECW

2nd Operand 1st Operand	#word	AX	rp <sup>Note</sup>	sfrp	saddrp	!addr16	SP	None
AX	ADDW SUBW CMPW		MOVW XCHW	MOVW	MOVW	MOVW	MOVW	
rp	MOVW	MOVW <sup>Note</sup>						INCW, DECW PUSH, POP
sfrp	MOVW	MOVW						
saddrp	MOVW	MOVW						
!addr16		MOVW						
SP	MOVW	MOVW						

**Note** Only when rp=BC, DE, HL.

**(3) Bit Manipulation Instruction**

MOV1, AND1, OR1, XOR1, SET1, CLR1, NOT1, BT, BF, BTCLR

2nd Operand 1st Operand	A.bit	sfr.bit	saddr.bit	PSW.bit	[HL].bit	CY	\$addr16	None
A.bit						MOV1	BT BF BTCLR	SET1 CLR1
sfr.bit						MOV1	BT BF BTCLR	SET1 CLR1
saddr.bit						MOV1	BT BF BTCLR	SET1 CLR1
PSW.bit						MOV1	BT BF BTCLR	SET1 CLR1
[HL].bit						MOV1	BT BF BTCLR	SET1 CLR1
CY	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1			SET1 CLR1 NOT1

**(4) Call Instruction/Branch Instruction**

CALL, CALLF, CALLT, BR, BC, BNC, BZ, BNZ, BT, BF, BTCLR, DBNZ

2nd Operand 1st Operand	AX	!addr16	!addr11	[addr5]	\$addr16
Basic instruction	BR	CALL, BR	CALLF	CALLT	BR, BC, BNC, BZ, BNZ
Compound instruction					BT, BF, BTCLR, DBNZ

**(5) Other Instruction**

ADJBA, ADJBS, BRK, RET, RETI, RETB, SEL, NOP, EI, DI, HALT, STOP

10. ELECTRICAL SPECIFICATIONS

Absolute Maximum Ratings (T<sub>A</sub> = 25 °C)

Parameter	Symbol	Test Conditions	Ratings	Unit			
Supply voltage	V <sub>DD</sub>		-0.3 to +7.0	V			
	AV <sub>DD</sub>		-0.3 to V <sub>DD</sub> +0.3	V			
	AV <sub>REF</sub>		-0.3 to V <sub>DD</sub> +0.3	V			
	AV <sub>SS</sub>		-0.3 to +0.3	V			
Input voltage	V <sub>I</sub>	P01-P03, P20-P24, P30-P37, P40-P47, P50-P53, P55-P57, P60-P67, X1, X2	-0.3 to V <sub>DD</sub> +0.3	V			
Output voltage	V <sub>O</sub>		-0.3 to V <sub>DD</sub> +0.3	V			
Analog input voltage	V <sub>AN</sub>	ANI0-ANI7	Analog input pins	AV <sub>SS</sub> - 0.3 to AV <sub>REF</sub> + 0.3	V		
Output current, high	I <sub>OH</sub>	Per pin		-10	mA		
		Total for P20-P24, P30-P37		-15	mA		
		Total for P01-P03, P40-P47, P50-P53, P55-P57, P64-P67		-15	mA		
Output current, low	I <sub>OL</sub> <sup>Note</sup>	Per pin	Peak value	30	mA		
			r.m.s. value	15	mA		
		Total for P40-P47, P50-P53, P55	Peak value	100	mA		
			r.m.s. value	70	mA		
		Total for P01-P03, P56, P57, P64-P67	Peak value	100	mA		
			r.m.s. value	70	mA		
		Total for P01-P03, P64-P67	Peak value	50	mA		
			r.m.s. value	20	mA		
		Total for P20-P24, P30-P37	Peak value	50	mA		
			r.m.s. value	20	mA		
		Operating ambient temperature	T <sub>A</sub>			-40 to +85	°C
		Storage temperature	T <sub>opt</sub>			-65 to +150	°C

**Note** The r.m.s. value should be calculated as follows: [r.m.s. value] = [Peak value] × √Duty

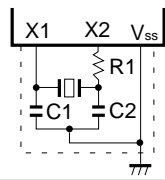
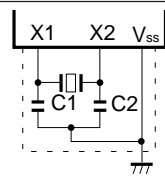
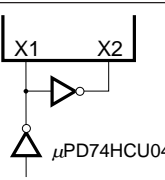
**Caution** Exposure to Absolute Maximum Ratings for extended periods may affect device reliability; exceeding the ratings could cause permanent damage. The parameters apply independently. The device should be operated within the limits specified.

Capacitance (T<sub>A</sub> = 25 °C, V<sub>DD</sub> = V<sub>SS</sub> = 0 V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Input capacitance	C <sub>IN</sub>	f = 1 MHz, unmeasured pins returned to 0 V.			15	pF
I/O capacitance	C <sub>IO</sub>	f = 1 MHz, unmeasured pins returned to 0 V.			15	pF
		P01-P03, P20-P24, P30-P37, P40-P47, P50-P53, P55-P57, P64-P67				

**Remark** Unless otherwise specified, dual-function pin characteristics are the same as port pin characteristics.

**Main System Clock Oscillator Characteristics** ( $T_A = -40$  to  $+85$  °C,  $V_{DD} = 2.7$  to  $5.5$  V)

Resonator	Recommended Circuit	Parameter	Test Conditions	MIN.	TYP.	MAX.	Unit
Ceramic resonator		Oscillation frequency ( $f_x$ ) <sup>Note 1</sup>	$V_{DD}$ = Oscillation voltage range	1		10	MHz
		Oscillation stabilization time <sup>Note 2</sup>	After $V_{DD}$ came to MIN. of oscillation voltage range			4	ms
Crystal resonator		Oscillation frequency ( $f_x$ ) <sup>Note 1</sup>		1	8.38	10	MHz
		Oscillation stabilization time <sup>Note 2</sup>	$V_{DD} = 4.5$ to $5.5$ V			10	ms
External clock		X1 input frequency ( $f_x$ ) <sup>Note 1</sup>		1.0		10.0	MHz
		X1 input high- and low-level widths ( $t_{xH}$ , $t_{xL}$ )		42.5		500	ns

- Notes 1.** Only the oscillator characteristics are shown. For the instruction execution time, refer to AC Characteristics.  
**2.** Time required for oscillation to stabilize after a reset or the STOP mode has been released.

**Caution** When using the oscillation circuit of the main system clock, wire the portion enclosed in dotted lines in the figures as follows to avoid adverse influences on the wiring capacitance:

- Keep the wiring length as short as possible.
- Do not cross the wiring over other signal lines.
- Do not route the wiring in the vicinity of lines through which a high fluctuating current flows.
- Always keep the ground point of the capacitor of the oscillation circuit at the same potential as  $V_{ss}$ .
- Do not connect the power source to a ground pattern through which a high current flows.
- Do not extract signals from the oscillation circuit.

**DC Characteristics** ( $T_A = -40$  to  $+85$  °C,  $V_{DD} = 2.7$  to  $5.5$  V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
Input voltage, high	$V_{IH1}$	P21, P23, P30-P32, P35-P37, P40-P47, P50-P53, P55-57, P60-P67	$0.7V_{DD}$		$V_{DD}$	V	
	$V_{IH2}$	P01-P03, P20, P22, P24, P33, P34, $\overline{RESET}$	$0.8V_{DD}$		$V_{DD}$	V	
	$V_{IH3}$	X1, X2	$V_{DD}-0.5$		$V_{DD}$	V	
Input voltage, low	$V_{IL1}$	P21, P23, P30-P32, P35-P37, P40-P47, P50-P53, P55-P57, P60-P67	0		$0.3V_{DD}$	V	
	$V_{IL2}$	P01-P03, P20, P22, P24, P33, P34, $\overline{RESET}$	0		$0.2V_{DD}$	V	
	$V_{IL3}$	X1, X2	0		0.4	V	
Output voltage, high	$V_{OH}$	$V_{DD} = 4.5$ to $5.5$ V, $I_{OH} = -1$ mA	$V_{DD}-1.0$			V	
		$I_{OH} = -100$ μA	$V_{DD}-0.5$			V	
Output voltage, low	$V_{OL1}$	P50-P53, P55-P57	$V_{DD} = 4.5$ to $5.5$ V, $I_{OH} = 15$ mA	0.4	2.0	V	
		P01-P03, P20-24, P30-P37, P40-P47, P64-P67	$V_{DD} = 4.5$ to $5.5$ V, $I_{OH} = 1.6$ mA		0.4	V	
	$V_{OL2}$	$I_{OL} = 400$ μA			0.5	V	
Input leakage current, high	$I_{LH1}$	$V_{IN} = V_{DD}$	P01-P03, P20-24, P30-P37, P40-P47, P50-P53, P55-P57, P60-P67, ANI0-ANI7, $\overline{RESET}$			3	μA
	$I_{LH2}$			X1, X2			20
Input leakage current, low	$I_{LIL1}$	$V_{IN} = 0$ V	P01-P03, P20-24, P30-P37, P40-P47, P50-P53, P55-P57, P60-P67, ANI0-ANI7, $\overline{RESET}$			-3	μA
	$I_{LIL2}$			X1, X2			-20
Output leakage current, high	$I_{LOH}$	$V_{OUT} = V_{DD}$				3	μA
Output leakage current, low	$I_{LOL}$	$V_{OUT} = 0$ V				-3	μA
Software pull-up resistance	R	$V_{IN} = 0$ V, P20-P24, P30-P37, P40-P47, P50-P53, P55-P57, P64-P67	$4.5 \leq V_{DD} \leq 5.5$ V	15	40	90	kΩ
			$2.7 \leq V_{DD} < 4.5$ V	20		500	kΩ

**Remark** Unless otherwise specified, dual-function pin characteristics are the same as port pin characteristics.

**DC Characteristics** ( $T_A = -40$  to  $+85$  °C,  $V_{DD} = 2.7$  to  $5.5$  V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
Supply current <sup>Note 1</sup>	I <sub>DD1</sub>	8.38-MHz crystal oscillation operating mode	$V_{DD} = 5.0\text{ V} \pm 10\%$ <sup>Note 2</sup>		6.5	19.5	mA
			$V_{DD} = 3.0\text{ V} \pm 10\%$ <sup>Note 3</sup>		0.7	2.1	mA
	I <sub>DD2</sub>	8.38-MHz crystal oscillation HALT mode	$V_{DD} = 5.0\text{ V} \pm 10\%$		1.4	4.2	mA
			$V_{DD} = 3.0\text{ V} \pm 10\%$		550	1650	μA
	I <sub>DD3</sub>	STOP mode	$V_{DD} = 5.0\text{ V} \pm 10\%$		0.1	20	μA
			$V_{DD} = 3.0\text{ V} \pm 10\%$		0.05	10	μA

**Notes 1.** Not including  $A_{VREF}$  current and port current.

**2.** High-speed mode operation (when processor clock control register (PCC) is set to 00H).

**3.** Low-speed mode operation (when PCC is set to 04H).

**Remark** Unless otherwise specified, dual-function pin characteristics are the same as port pin characteristics.

**AC Characteristics** ( $T_A = -40$  to  $+85$  °C,  $V_{DD} = 2.7$  to  $5.5$  V)

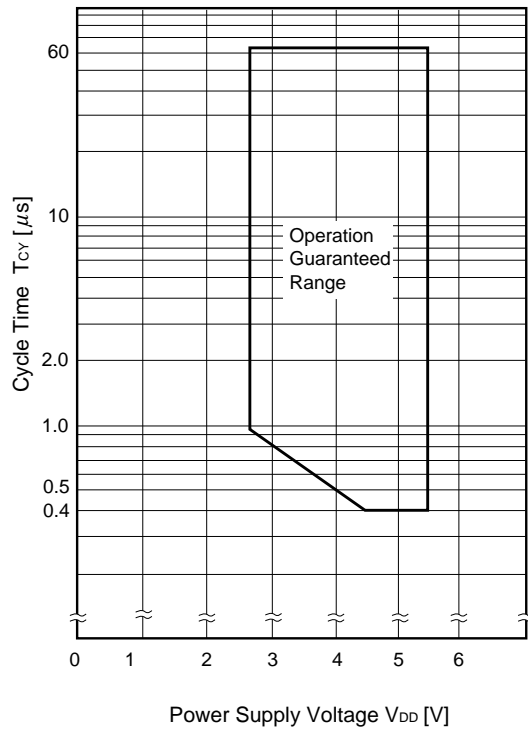
**(1) Basic Operation**

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Cycle time (minimum instruction execution time)	$T_{CY}$	$V_{DD} = 4.5$ to $5.5$ V	0.4		64	$\mu s$
			0.96		64	$\mu s$
T11, T12 input frequency	$f_{TI}$	$V_{DD} = 4.5$ to $5.5$ V	0		4	MHz
			0		275	kHz
T11, T12 input high-/low-level width	$t_{TIH}$	$V_{DD} = 4.5$ to $5.5$ V	100			ns
	$t_{TIL}$		1.8			$\mu s$
Interrupt input high-/low-level width	$t_{INTH}$	INTP1-INTP3	10			$\mu s$
	$t_{INTL}$	KR0-KR7	10			$\mu s$
RESET low-level width	$t_{RSL}$		10			$\mu s$

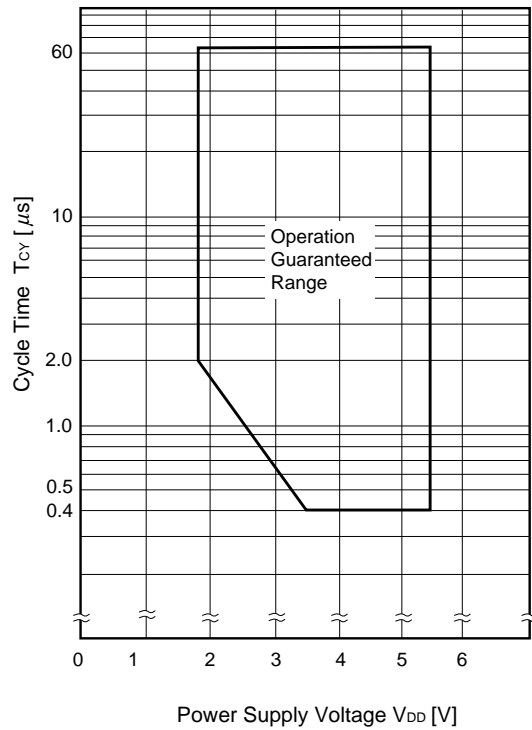
μPD780001

μPD78P018F (Reference)

**$T_{CY}$  vs  $V_{DD}$  (Main System Clock Operation)**



**$T_{CY}$  vs  $V_{DD}$  (Main System Clock Operation)**



**Caution** The operation guaranteed range of the μPD780001 is different from that of the μPD78P018F.

(2) Serial Interface (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 2.7 to 5.5 V)

(a) 3-wire serial I/O mode ( $\overline{\text{SCK1}}$  ... internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
SCK1 cycle time	t <sub>KCY1</sub>	V <sub>DD</sub> = 4.5 to 5.5 V	800			ns
			1600			ns
SCK1 high-/low-level width	t <sub>KH1</sub> , t <sub>KL1</sub>	V <sub>DD</sub> = 4.5 to 5.5 V	t <sub>KCY1</sub> /2-50			ns
			100			ns
S11 setup time (to SCK1 ↑)	t <sub>SIK1</sub>	V <sub>DD</sub> = 4.5 to 5.5 V	100			ns
			150			ns
S11 hold time (from $\overline{\text{SCK1}}$ ↑)	t <sub>KSI1</sub>		400			ns
$\overline{\text{SCK1}}$ ↓ → SO1 output delay time	t <sub>KSO1</sub>	C = 100 pF <sup>Note</sup>			300	ns

**Note** C is the SO1 output line load capacitance.

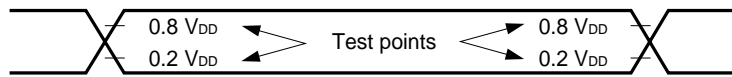
(b) 3-wire serial I/O mode ( $\overline{\text{SCK1}}$  ... external clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
SCK1 cycle time	t <sub>KCY2</sub>	V <sub>DD</sub> = 4.5 to 5.5 V	800			ns
			1600			ns
SCK1 high-/low-level width	t <sub>KH2</sub> , t <sub>KL2</sub>	V <sub>DD</sub> = 4.5 to 5.5 V	400			ns
			800			ns
S11 setup time (to $\overline{\text{SCK1}}$ ↑)	t <sub>SIK2</sub>		100			ns
						ns
S11 hold time (from $\overline{\text{SCK1}}$ ↑)	t <sub>KSI2</sub>		400			ns
$\overline{\text{SCK1}}$ ↓ → SO1 output delay time	t <sub>KSO2</sub>	C = 100 pF <sup>Note</sup>			300	ns
SCK1 rise, fall time	t <sub>R</sub> , t <sub>F</sub>	V <sub>DD</sub> = 4.5 to 5.5 V			1000	ns

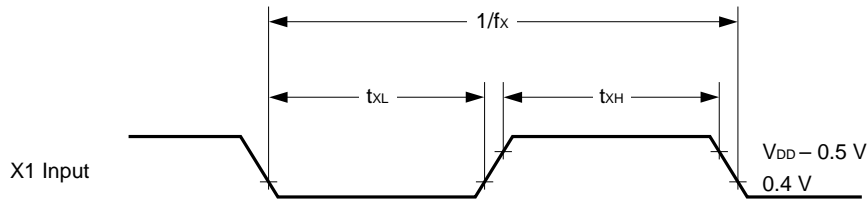
**Note** C is the SO1 output line load capacitance.



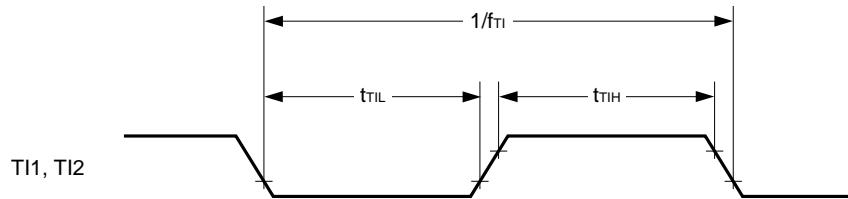
AC Timing Test Point (Excluding X1 Input)



Clock Timing

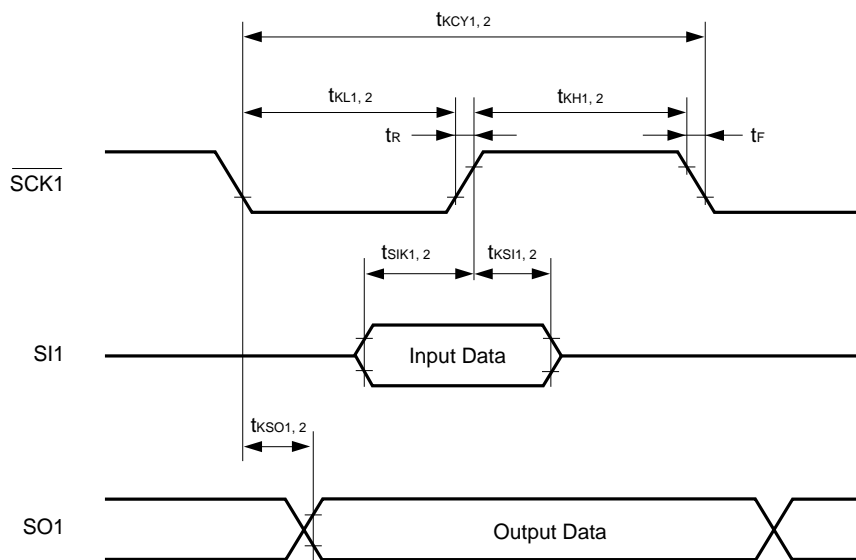


TI Timing



Serial Transfer Timing

3-wire serial I/O mode:



**A/D Converter Characteristics** ( $T_A = -40$  to  $+85$  °C,  $AV_{DD} = V_{DD} = 4.2$  to  $5.5$  V,  $AV_{SS} = V_{SS} = 0$  V)  
 ( $T_A = -10$  to  $+85$  °C,  $AV_{DD} = V_{DD} = 4.0$  to  $5.5$  V,  $AV_{SS} = V_{SS} = 0$  V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Resolution			8	8	8	bit
Total error <sup>Note</sup>					0.6	%
Conversion time	$t_{CONV}$		19.1		200	μs
Sampling time	$t_{SAMP}$		$24/f_x$			μs
Analog input voltage	$V_{IAN}$		$AV_{SS}$		$AV_{REF}$	V
Reference voltage	$AV_{REF}$		2.7		$AV_{DD}$	V
$AV_{REF}$ - $AV_{SS}$ resistance	$RA_{REF}$		4	14		kΩ

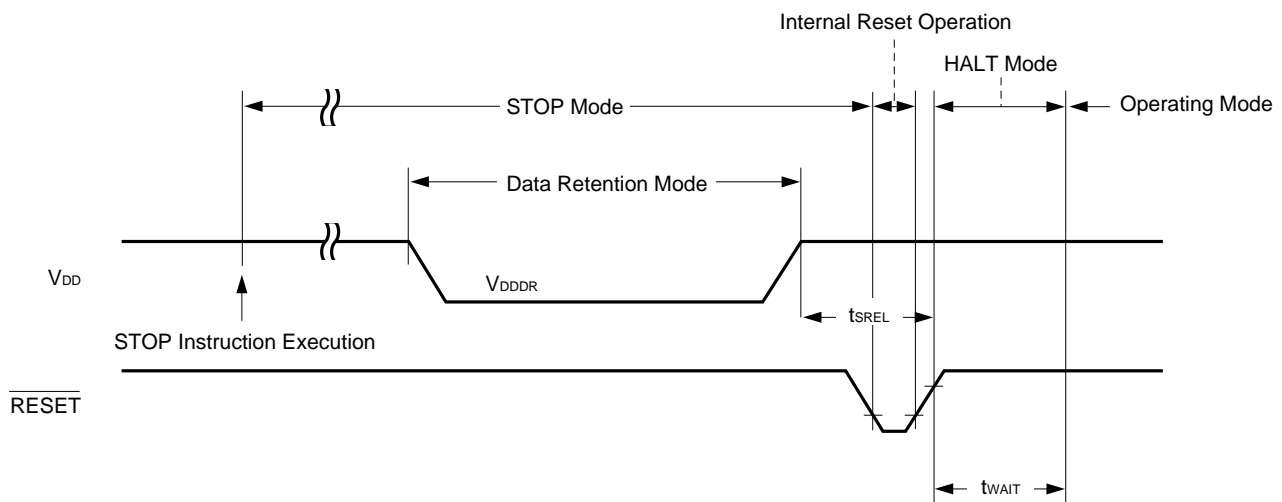
**Note** Excluding quantization error ( $\pm 1/2$  LSB). Shown as a percentage of the full scale value.

**Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics** ( $T_A = -40$  to  $+85$  °C)

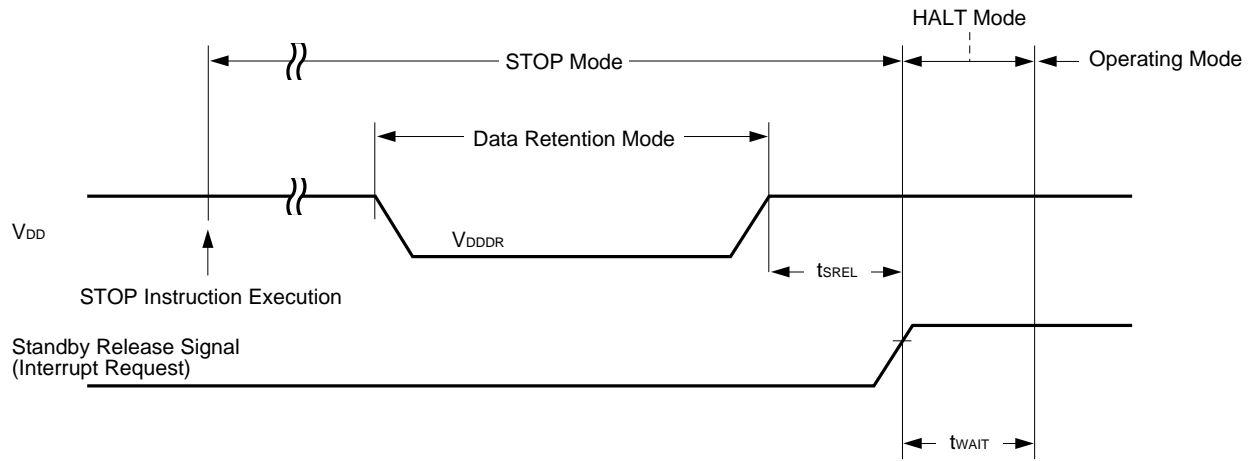
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	$V_{DDDR}$		2.0		5.5	V
Data retention supply current	$I_{DDDR}$	$V_{DDDR} = 2.0$ V		0.1	10	μA
Release signal setup time	$t_{SREL}$		0			μs
Oscillation stabilization wait time	$t_{WAIT}$	Release by $\overline{RESET}$		$2^{18}/f_x$		ms
		Release by interrupt		<b>Note</b>		ms

**Note**  $2^{13}/f_x$  or  $2^{15}/f_x$ - $2^{18}/f_x$  can be selected by bit 0-bit 2 (OSTS0-OSTS2) of oscillation stabilization time selection register (OSTS).

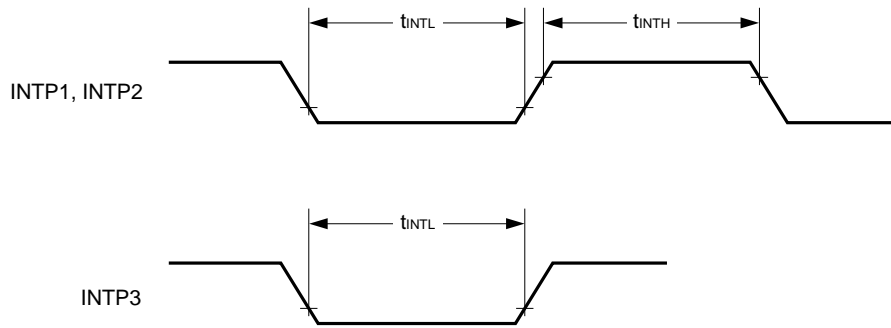
**Data Retention Timing (STOP mode released by  $\overline{RESET}$ )**



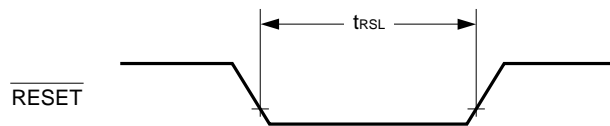
**Data Retention Timing (Standby release signal: STOP mode released by interrupt signal)**



**Interrupt Input Timing**

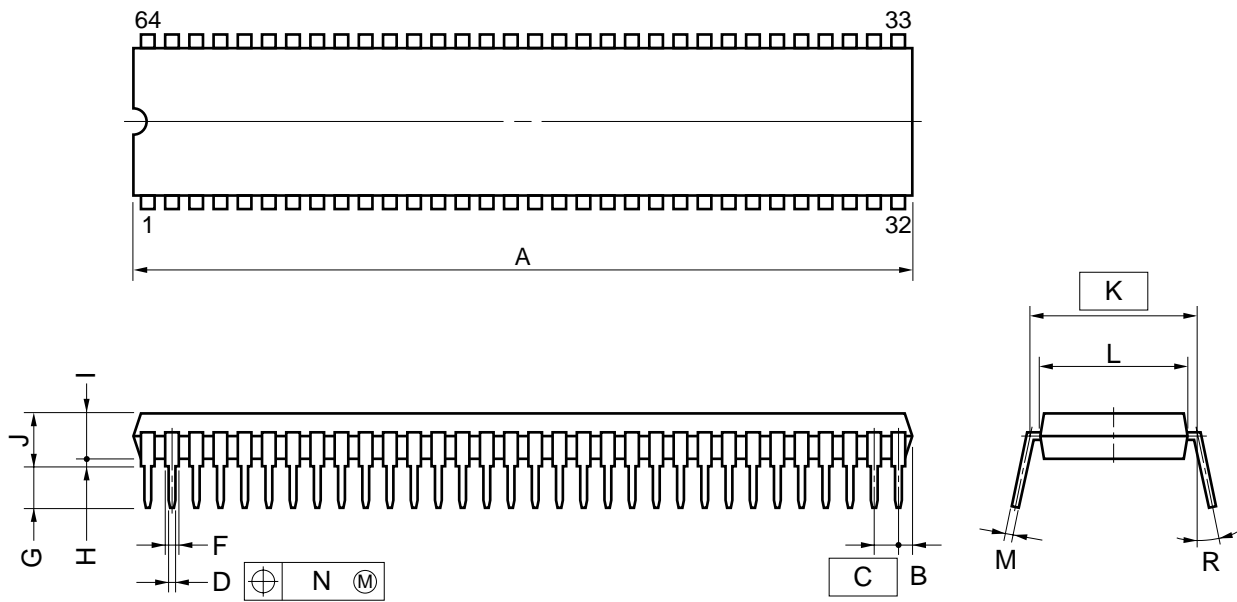


**RESET Input Timing**



11. PACKAGE DRAWINGS

64 PIN PLASTIC SHRINK DIP (750 mil)



NOTE

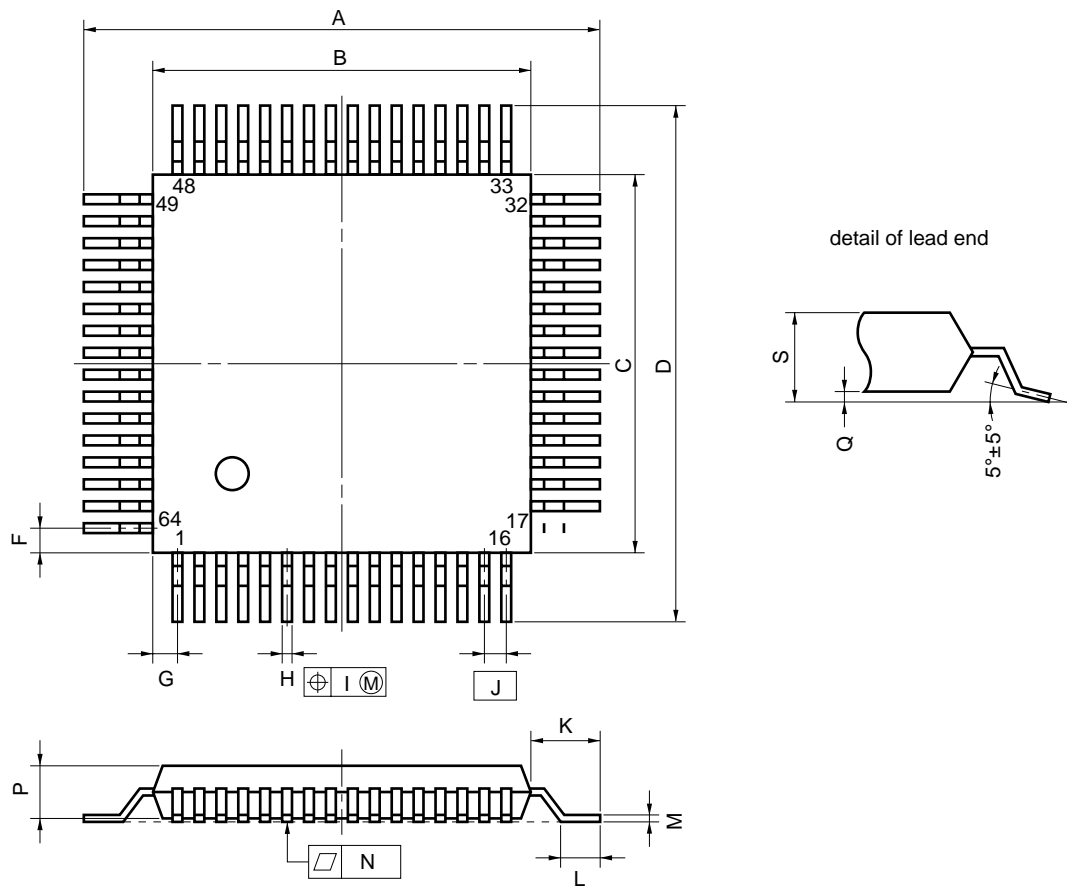
- 1) Each lead centerline is located within 0.17 mm (0.007 inch) of its true position (T.P.) at maximum material condition.
- 2) Item "K" to center of leads when formed parallel.

ITEM	MILLIMETERS	INCHES
A	58.68 MAX.	2.311 MAX.
B	1.78 MAX.	0.070 MAX.
C	1.778 (T.P.)	0.070 (T.P.)
D	0.50±0.10	0.020 <sup>+0.004</sup> <sub>-0.005</sub>
F	0.9 MIN.	0.035 MIN.
G	3.2±0.3	0.126±0.012
H	0.51 MIN.	0.020 MIN.
I	4.31 MAX.	0.170 MAX.
J	5.08 MAX.	0.200 MAX.
K	19.05 (T.P.)	0.750 (T.P.)
L	17.0	0.669
M	0.25 <sup>+0.10</sup> <sub>-0.05</sub>	0.010 <sup>+0.004</sup> <sub>-0.003</sub>
N	0.17	0.007
R	0~15°	0~15°

P64C-70-750A,C-1

**Remark** The shape and material of the ES product is the same as those of the mass-produced product.

64 PIN PLASTIC QFP (□14)



NOTE

Each lead centerline is located within 0.15 mm (0.006 inch) of its true position (T.P.) at maximum material condition.

P64GC-80-AB8-3

ITEM	MILLIMETERS	INCHES
A	17.6±0.4	0.693±0.016
B	14.0±0.2	0.551 <sup>+0.009</sup> <sub>-0.008</sub>
C	14.0±0.2	0.551 <sup>+0.009</sup> <sub>-0.008</sub>
D	17.6±0.4	0.693±0.016
F	1.0	0.039
G	1.0	0.039
H	0.35±0.10	0.014 <sup>+0.004</sup> <sub>-0.005</sub>
I	0.15	0.006
J	0.8 (T.P.)	0.031 (T.P.)
K	1.8±0.2	0.071±0.008
L	0.8±0.2	0.031 <sup>+0.009</sup> <sub>-0.008</sub>
M	0.15 <sup>+0.10</sup> <sub>-0.05</sub>	0.006 <sup>+0.004</sup> <sub>-0.003</sub>
N	0.10	0.004
P	2.55	0.100
Q	0.1±0.1	0.004±0.004
S	2.85 MAX.	0.112 MAX.

Remark The shape and material of the ES product is the same as those of the mass-produced product.

\* 12. RECOMMENDED SOLDERING CONDITIONS

It is recommended that the μPD780001 be soldered under the following conditions. For details on the recommended soldering conditions, refer to information document "Semiconductor Device Mounting Technology Manual" (IEI-1207).

For soldering methods and conditions other than those recommended, please contact an NEC sales representative.

Table 12-1. Surface Mount Type Soldering Conditions

μPD780001GC-XXX-AB8: 64-pin plastic QFP (14 × 14 mm)

Soldering Method	Soldering Conditions	Symbol
Infrared ray reflow	Package peak temperature: 235°C, Time: 30 seconds max. (210°C min.), Number of times: 2 max. < Cautions > (1) Wait for the device temperature to return to normal after the first reflow before starting the second reflow. (2) Do not perform flux cleaning with water after the first reflow.	IR35-00-2
VPS	Package peak temperature: 215°C, Time: 40 seconds max. (200°C min.), Number of times: 2 max. < Cautions > (1) Wait for the device temperature to return to normal after the first reflow before starting the second reflow. (2) Do not perform flux cleaning with water after the first reflow.	VP15-00-2
Wave soldering	Solder temperature: 260°C max., Time: 10 seconds max., Number of times: 1, Preheating temperature: 120 °C max. (package surface temperature)	WS60-00-1
Partial heating	Pin temperature: 300°C max. Time: 3 seconds max. (per device side)	—

**Caution** Do not use different soldering methods together (except for partial heating method).

Table 12-2. Through-Hole Type Soldering Conditions

μPD780001CW-XXX: 64-pin plastic shrink DIP (750 mil)

Soldering Method	Soldering Conditions
Wave soldering (pin only)	Solder temperature: 260°C max., Time: 10 seconds max.
Partial heating	Pin temperature: 300°C max., Time: 3 seconds max. (per pin)

**Caution** Apply wave soldering only to the pins and be careful so as not to bring solder into direct contact with the package.

**APPENDIX A. DEVELOPMENT TOOLS**

The following development tools are available for system development using the μPD780001.

**Language Processing Software**

RA78K/0 <sup>Notes 1, 2, 3</sup>	Assembler package common to the 78K/0 series	
CC78K/0 <sup>Notes 1, 2, 3</sup>	C compiler package common to the 78K/0 series	
DF780001 <sup>Notes 1, 2, 3</sup>	μPD780001 device file	*
CC78K/0-L <sup>Notes 1, 2, 3</sup>	C compiler library source file common to the 78K/0 series	

**PROM Writing Tools**

PG-1500	PROM programmer	
PA-78P018CW PA-78P018GC PA-78P018KK-S	Programmer adapter connected to the PG-1500	
PG-1500 Controller <sup>Notes 1, 2</sup>	Control program used for the PG-1500	

**Debugging Tools**

IE-78000-R	In-circuit emulator common to the 78K/0 series	
IE-78000-R-BK	Break board common to the 78K/0 series	
IE-78014-R-EM-A	Emulation board common to the μPD78018F subseries, etc.	
EP-78240CW-R EP-78240GC-R	Emulation probe common to the μPD78244 subseries	
EV-9200GC-64	Socket to be mounted on user system board created for the 64-pin plastic QFP	
SM78K0 <sup>Notes 4, 5</sup>	System simulator common to the 78K/0 series	
SD78K/0 <sup>Notes 1, 2</sup>	IE-78000-R screen debugger	
DF780001 <sup>Notes 1, 2, 4, 5</sup>	μPD780001 device file	*

**Real-Time OS**

MX78K0 <sup>Notes 1, 2, 3</sup>	78K/0 series OS	
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**Fuzzy Inference Development Support System**

FE9000 <sup>Note 1</sup> /FE9200 <sup>Note 5</sup>	Fuzzy knowledge data creation tool
FT9080 <sup>Note 1</sup> /FT9085 <sup>Note 2</sup>	Translator
FI78K0 <sup>Notes 1, 2</sup>	Fuzzy inference module
FD78K0 <sup>Notes 1, 2</sup>	Fuzzy inference debugger

- Notes**
1. Based on PC-9800 series (MS-DOS™)
  2. Based on IBM PC/AT™ (PC DOS™)
  3. Based on HP9000 series 300™, HP9000 series 700™ (HP-UX™), SPARCstation™ (SunOS™), and EWS-4800 series (EWS-UX/V)
  4. Based on PC-9800 series (MS-DOS + Windows™)
  5. Based on IBM PC/AT (PC DOS + Windows)

**Remark** RA78K/0, CC78K/0, SM78K0, and SD78K/0 are used in combination with the DF780001.



## APPENDIX B. RELATED DOCUMENTS

## Documents Related to Devices

Document Name	Document No.	
	Japanese	English
μPD780001 User's Manual	In preparation	Planned
78K/0 Series User's Manual—Instructions	IEU-849	IEU-1372
78K/0 Series Instruction Table	IEM-5522	—
78K/0 Series Instruction Set	IEM-5521	—
μPD780001 Special Function Register Table	Planned	—

## Documents Related to Development Tools (User's Manual)

Document Name		Document No.	
		Japanese	English
RA78K Series Assembler Package	Operation	EEU-809	EEU-1399
	Language	EEU-815	EEU-1404
RA78K Series Structured Assembler Preprocessor		EEU-817	EEU-1402
CC78K Series C Compiler	Operation	EEU-656	EEU-1280
	Language	EEU-655	EEU-1284
CC78K/0 C Compiler Application Note	Programming know-how	EEA-618	Planned
CC78K Series Library Source File		EEU-777	—
PG-1500 PROM Programmer		EEU-651	EEU-1335
PG-1500 Controller PC-9800 Series (MS-DOS) Based		EEU-704	Planned
PG-1500 Controller IBM PC Series (PC DOS) Based		EEU-5008	EEU-1291
IE-78000-R		EEU-810	EEU-1398
IE-78000-R-BK		EEU-867	EEU-1427
IE-78014-R-EM-A		EEU-962	EEU-1487
EP-78240		EEU-986	EEU-1513
SM78K0 System Simulator	Reference	EEU-5002	Planned
SM78K Series System Simulator	External parts user open interface specification	U10092J	Planned
SD78K/0 Screen Debugger PC-9800 Series (MS-DOS) Based	Introduction	EEU-852	—
	Reference	EEU-816	—
SD78K/0 Screen Debugger IBM PC/AT (PC DOS) Based	Introduction	EEU-5024	EEU-1414
	Reference	EEU-993	EEU-1413

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**Caution** The contents of the documents listed above are subject to change without prior notice. Make sure to use the latest edition when starting design.

**Documents Related to Embedded Software (User's Manual)**

Document Name		Document No.	
		Japanese	English
78K/0 Series OS	MX78K0 Basic	EEU-5010	—
Fuzzy Knowledge Data Creation Tool		EEU-829	EEU-1438
78K/0, 78K/II, and 87AD Series Fuzzy Inference Development Support System–Translator		EEU-862	EEU-1444
78K/0 Series	Fuzzy Inference Development Support System Fuzzy Inference Module	EEU-858	EEU-1441
78K/0 Series	Fuzzy Inference Development Support System Fuzzy Inference Debugger	EEU-921	EEU-1458

**Other Documents**

Document Name		Document No.	
		Japanese	English
Semiconductor Package Manual		IEI-635	IEI-1213
Semiconductor Device Mounting Technology Manual		IEI-616	IEI-1207
Quality Grades on NEC Semiconductor Devices		IEI-620	IEI-1209
NEC Semiconductor Device Reliability/Quality Control System		IEM-5068	—
Electrostatic Discharge (ESD) Test		MEM-539	—
Guide to Quality Assurance for Semiconductor Devices		MEI-603	MEI-1202
Microcontroller-Related Product Guide – Third Party Products –		MEI-604	—

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## NOTES FOR CMOS DEVICES

### ① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note: Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

### ② HANDLING OF UNUSED INPUT PINS FOR CMOS

Note: No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to  $V_{DD}$  or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

### ③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note: Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

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NEC devices are classified into the following three quality grades:

“Standard”, “Special”, and “Specific”. The Specific quality grade applies only to devices developed based on a customer designated “quality assurance program” for a specific application. The recommended applications of a device depend on its quality grade, as indicated below. Customers must check the quality grade of each device before using it in a particular application.

Standard: Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots

Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)

Specific: Aircrafts, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

The quality grade of NEC devices in “Standard” unless otherwise specified in NEC's Data Sheets or Data Books. If customers intend to use NEC devices for applications other than those specified for Standard quality grade, they should contact NEC Sales Representative in advance.

Anti-radioactive design is not implemented in this product.